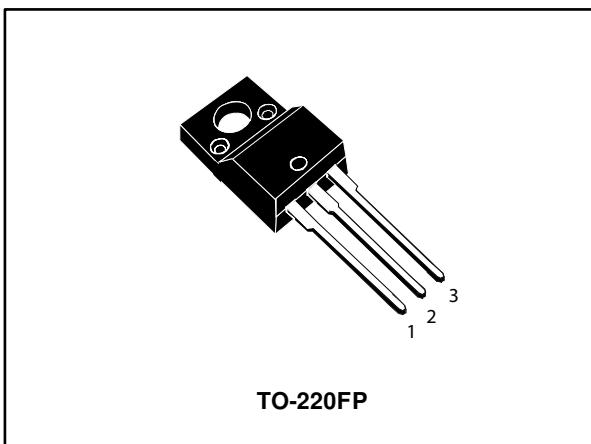


N-channel 650 V, 0.087 Ω typ., 32 A MDmesh™ M2 Power MOSFET in a TO-220FP package

Datasheet - production data



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D
STF40N65M2	650 V	0.099 Ω	32 A

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

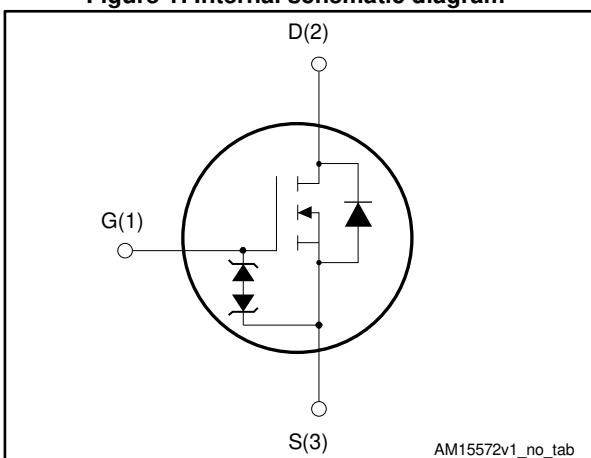


Table 1: Device summary

Order code	Marking	Package	Packaging
STF40N65M2	40N65M2	TO-220FP	Tube

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	32	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	20	A
$I_{DM}^{(2)}$	Drain current (pulsed)	128	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	25	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(4)}$	MOSFET dv/dt ruggedness	50	V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1\text{ s}$; $T_C = 25^\circ\text{C}$)	2500	V
T_{stg}	Storage temperature	- 55 to 150	$^\circ\text{C}$
T_j	Max. operating junction temperature	150	

Notes:

(1) Limited by maximum junction temperature.

(2) Pulse width limited by safe operating area.

(3) $I_{SD} \leq 32\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$; $V_{DS\ peak} < V_{(BR)DSS}$, $V_{DD} = 400\text{ V}$ (4) $V_{DS} \leq 520\text{ V}$ **Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	3.13	$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.50	$^\circ\text{C/W}$

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	3	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	820	mJ

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
I_{DSS}	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 10	μA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 16 \text{ A}$		0.087	0.099	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	2355	-	pF
C_{oss}	Output capacitance		-	102	-	pF
C_{rss}	Reverse transfer capacitance		-	2.7	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$	-	380	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz open drain}$	-	4.5	-	Ω
Q_g	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 32 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 15: "Gate charge test circuit")	-	56.5	-	nC
Q_{gs}	Gate-source charge		-	8	-	nC
Q_{gd}	Gate-drain charge		-	24	-	nC

Notes:

⁽¹⁾ $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 325 \text{ V}$, $I_D = 16 \text{ A}$ $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see <i>Figure 14: "Switching times test circuit for resistive load"</i> and <i>Figure 19: "Switching time waveform"</i>)	-	15	-	ns
t_r	Rise time		-	10	-	ns
$t_{d(off)}$	Turn-off-delay time		-	96.5	-	ns
t_f	Fall time		-	12	-	ns

Table 8: Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		32	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		128	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$, $I_{SD} = 32 \text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 32 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: " Test circuit for inductive load switching and diode recovery times"</i>)	-	468		ns
Q_{rr}	Reverse recovery charge		-	8.7		μC
I_{RRM}	Reverse recovery current		-	37.5		A
t_{rr}	Reverse recovery time	$I_{SD} = 32 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$, $T_j = 150^\circ\text{C}$ (see <i>Figure 16: " Test circuit for inductive load switching and diode recovery times"</i>)	-	610		ns
Q_{rr}	Reverse recovery charge		-	11.7		μC
I_{RRM}	Reverse recovery current		-	39		A

Notes:

(1)Pulse width is limited by safe operating area

(2)Pulse test: pulse duration = 300 μs , duty cycle 1.5%

2.2 Electrical characteristics (curves)

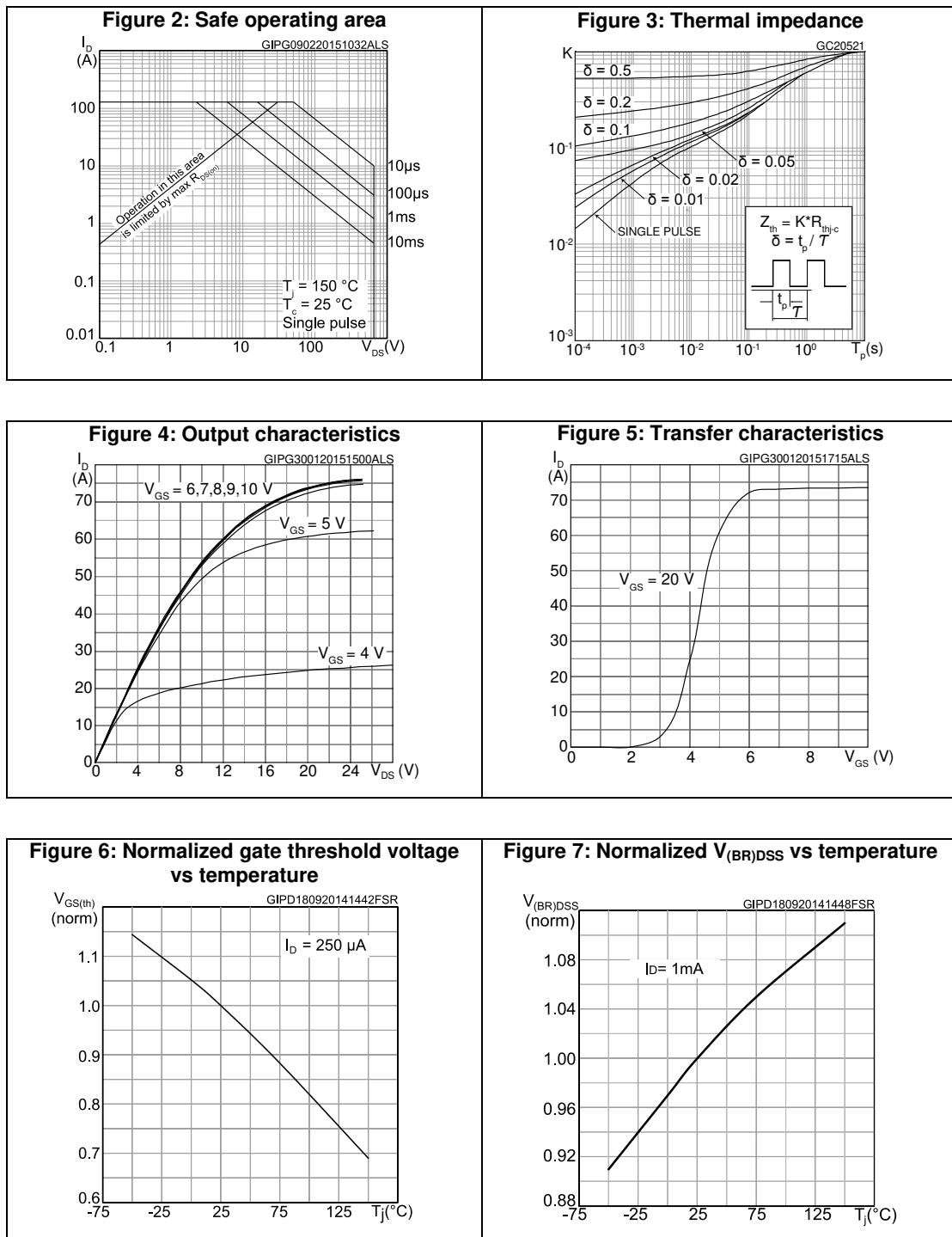
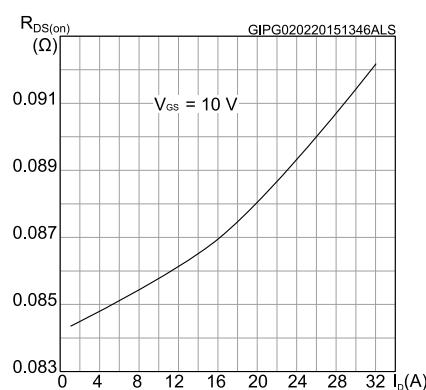
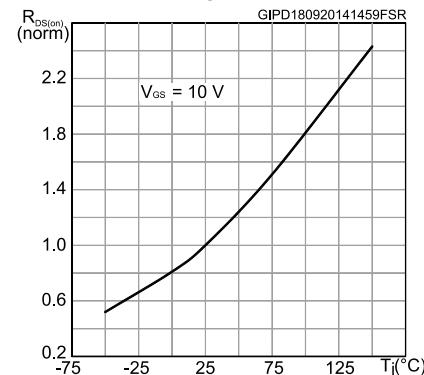
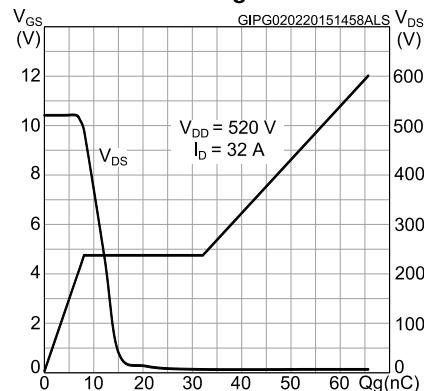
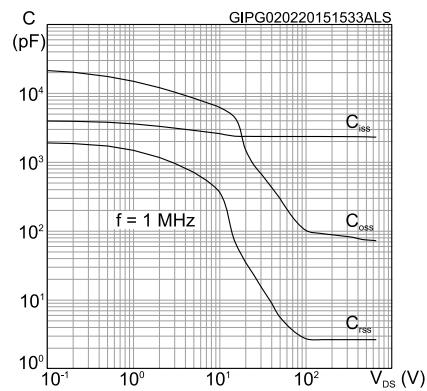
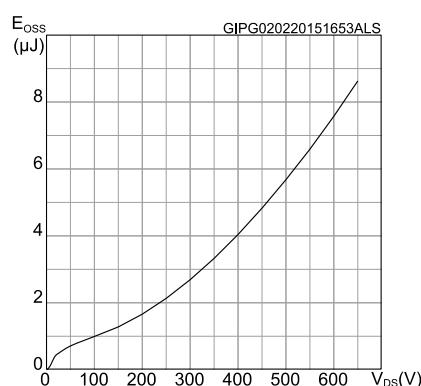
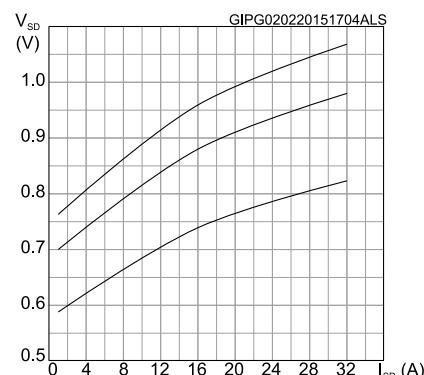


Figure 8: Static drain-source on-resistance**Figure 9: Normalized on-resistance vs. temperature****Figure 10: Gate charge vs. gate-source voltage****Figure 11: Capacitance variations****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

3 Test circuits

Figure 14: Switching times test circuit for resistive load

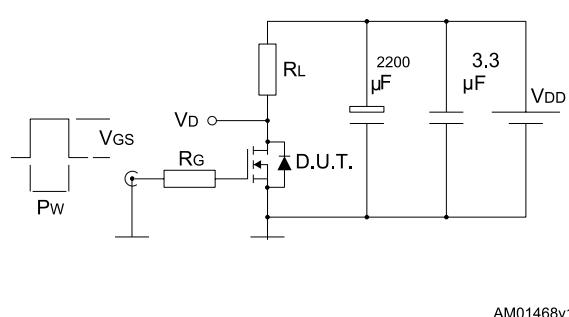


Figure 16: Test circuit for inductive load switching and diode recovery times

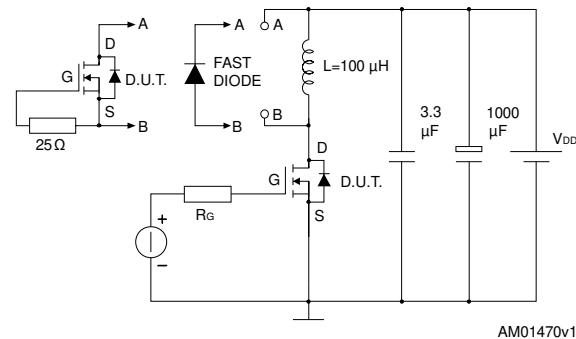


Figure 15: Gate charge test circuit

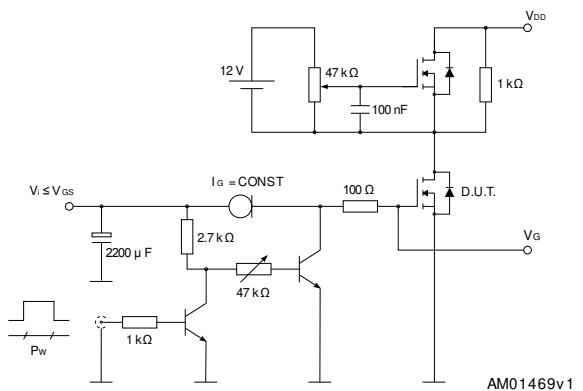


Figure 17: Unclamped inductive load test circuit

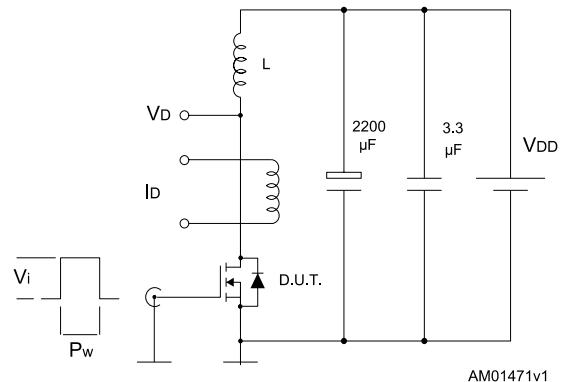


Figure 18: Unclamped inductive waveform

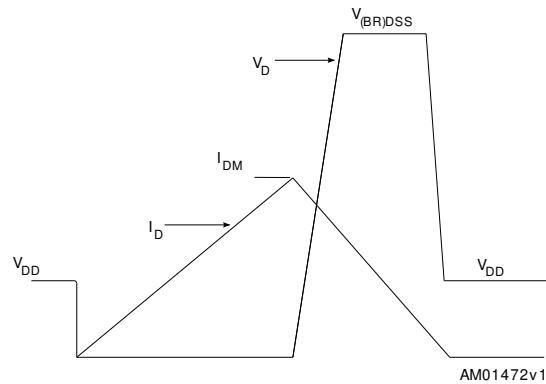
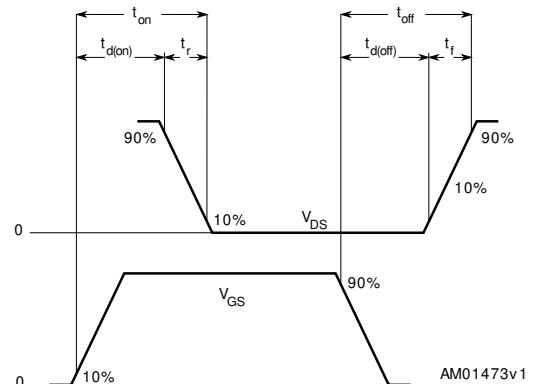


Figure 19: Switching time waveform

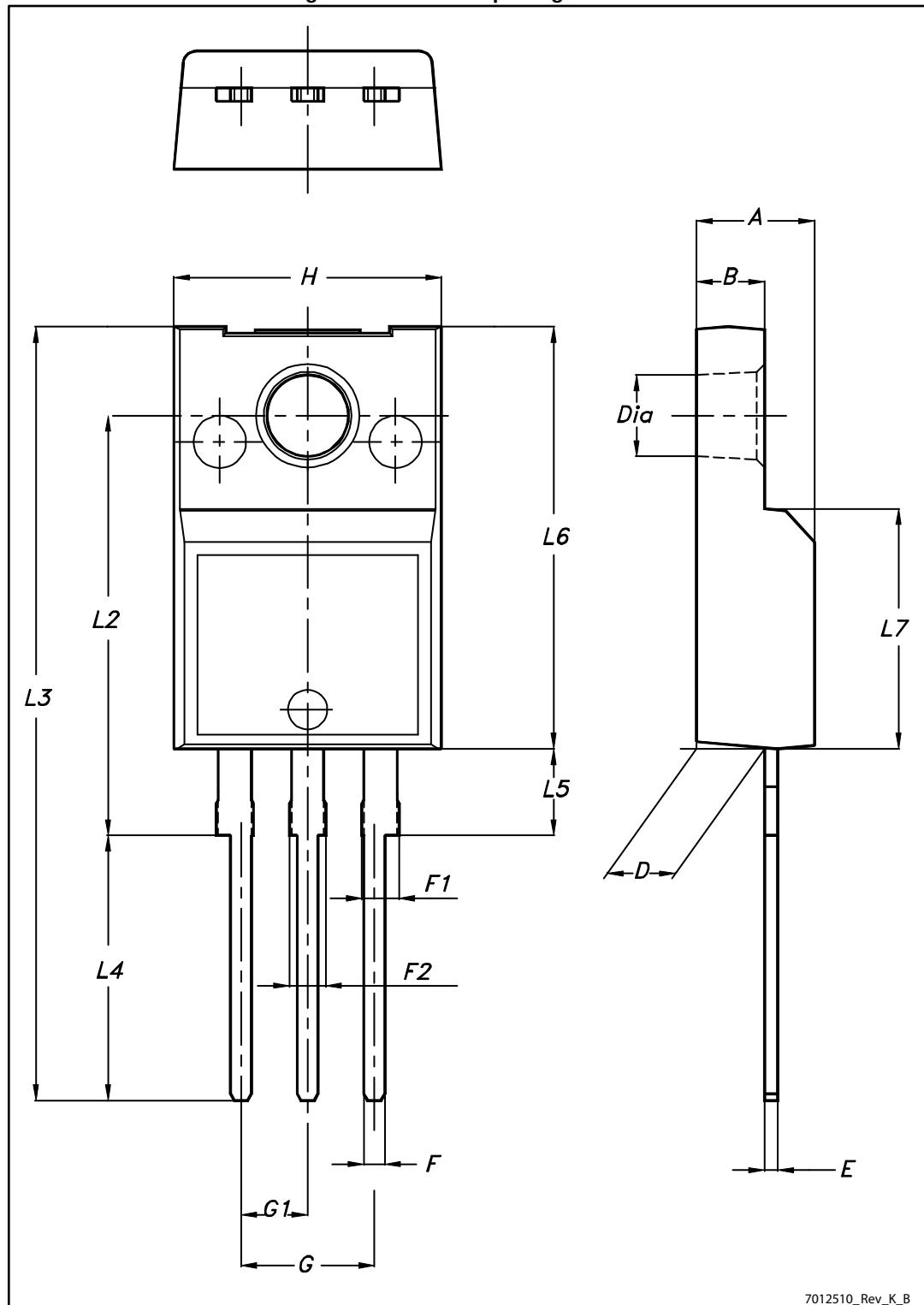


4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
ECOPACK® is an ST trademark.

4.1 TO-220FP package information

Figure 20: TO-220FP package outline



7012510_Rev_K_B

Table 9: TO-220FP mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
09-Feb-2014	1	First release.

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